

# Section 11

## ABBREVIATIONS

### **Massachusetts Institute of Technology**

ACC .....Advanced Concepts Committee (MIT LL)  
CAES .....Center for Advanced Engineering Study  
ChE .....Department of Chemical Engineering  
ChemE .....Department of Chemical Engineering  
CICS .....Center for Integrated Circuits and Systems  
CIPS .....Center for Integrated Photonic Systems  
CMI .....Cambridge-MIT Institute  
CMSE .....Center for Materials Science and Engineering  
CSR .....Center for Space Research  
DMA .....Dupont-MIT Alliance  
DMSE .....Department of Materials Science and Engineering  
EECS .....Department of Electrical Engineering and Computer Science  
HST .....Health Sciences and Technology, Harvard-MIT  
ICL .....Integrated Circuits Laboratory  
ISN .....Institute for Soldier Nanotechnologies  
ITRC .....Intelligent Transportation Research Center  
LEES .....Laboratory for Electromagnetic and Electronic Systems  
LFM .....Leaders for Manufacturing  
MIG .....Microsystems Industrial Group  
MIT .....Massachusetts Institute of Technology  
MNSL .....Micro & Nano Systems Laboratory  
MPC .....Materials Processing Center  
MTL .....Microsystems Technology Laboratories  
NSL .....NanoStructures Laboratory  
RLE .....Research Laboratory of Electronics  
SMA .....Singapore-MIT Alliance  
SML .....Space Microstructures Laboratory  
SOE .....School of Engineering  
TRL .....Technology Research Laboratory  
UROP .....Undergraduate Research Opportunities Program

### **Private Industry**

AMD .....Advanced Micro Devices  
CSDL .....Charles Stark Draper Laboratory  
HP .....Hewlett-Packard  
IBM .....International Business Machines Corporation  
KIMM .....Korea Institute of Machinery and Materials  
MARCO .....Microelectronics Advanced Research Corporation  
C2S2 .....Center for Circuits and Systems Solutions  
GSRC .....Gigascale Systems Research Center  
IFC .....Interconnect Focus Center  
MSD .....Center for Materials, Structures and Devices  
MGH .....Massachusetts General Hospital  
NTT .....Nippon Telephone and Telegraph  
SIA .....Semiconductor Industry Association  
SRC .....Semiconductor Research Corporation  
TI .....Texas Instruments

### **Government**

AFOSR .....U.S. Air Force Office of Scientific Research  
AFRL .....Air Force Research Laboratories  
ARDA .....Advanced Research and Development Activity  
ARL .....Army Research Labotraries  
ARO MURI .....Army Research Office M  
CSE .....Consortium on Superconducting Electronic  
DARPA .....Defense Advanced Research Projects Agency  
DOD .....Department of Defense  
DOE .....Department of Energy  
DURINT .....Defense University Initiative on Nanotechnology  
JPL .....Jet Propulsion Laboratories  
JSEP .....Joint Services Electronics Program  
LANL .....Los Alamos National Laboratory  
MDA .....Missile Defense Agency  
MRSEC .....Materials Research Science and Engineering Center  
MURI .....Multi University Research Initiative  
NASA .....National Aeronautics and Space Administration  
NCIPT .....National Center for Integrated Photonics Technology  
NDSEG .....National Defense Science and Engineering Graduate  
NIH .....National Institutes of Health  
NCI .....National Cancer Institute  
NCRR .....National Center for Research Resources  
NIDDK .....National Institute of Diabetes and Digestive and Kidney Diseases  
NIBIB .....National Institute of Biomedical Imaging and BioEngineering  
NHLBI .....National Heart, Lung, and Blood Institute  
NIST .....National Institute of Standards and Technology  
NOAA .....National Atmospheric and Oceanographic Administration  
NREL .....National Renewable Energy Laboratory  
NRL .....Naval Research Laboratory  
NSA .....National Security Administration  
NSF .....National Science Foundation  
CMSE .....Center for Materials Science and Engineering  
MRSEC .....Materials Research Science and Engineering Centers  
NIRT .....Nanotechnology and Interdisciplinary Research Initiative  
SGER .....Small Grant for Exploratory Research  
ONR .....Office of Naval Research

### **Other**

CFI	CAD Framework Initiative
CIE	Commission International de l'Eclairage
CIM	Computer Integrated Manufacturing
IEEE	Institute of Electrical and Electronics Engineers
IEDM	International Electronic Devices Meeting
IME	Institute of Microelectronics, Singapore
IMEC	Interuniversity MicroElectronics Center
MCNC	Microelectronics Center of North Carolina
MRS	Materials Research Society
NATO	North Atlantic Treaty Organization
NTCIP	National Transportation Communications for Intelligent Transportation
WiMAX	Worldwide Interoperability for Microwave Access, Inc.

### **Technical**

AAO	Anodic aluminum oxide
ACEO	AC electro-osmosis
ACPR	Adjacent channel power ratio
ADC	Analog-to-digital converter
AFM	Atomic force microscope
ALD	Atomic layer deposition
AMOL	Absorbance-two-wavelength scheme
APCVD	Atmospheric pressure chemical vapor deposition
ASIC	Application-specific integrated circuit
BEOL	Back-end-of-line
BER	Bit-error-rate
BiCMOS	Bipolar complementary metal oxide semiconductor
BPSK	Binary phase shift keying
BPV	Back-propagation of variance
BTBT	Band-to-band tunneling
CAD	Computer aided design
CATV	Category V
CBSC	Comparator-based switched-capacitor circuit
CCD	Charge couple device
CCR	Critically coupled resonator
CDR	Clock and data recovery
CFB	Cartesian feedback
CFT	Clock feed-through
CML	Current mode latch
CMOS	Complementary metal oxide semiconductor
CMP	Chemical mechanical planarization
CNT	Carbon nanotube
COC	Cyclic olefin copolymer
COIL	Chemical oxygen iodine laser
CV	Capacitance voltage
CVD	Chemical vapor deposition
DAC	Digital-to-analog converter
DBR	Dielectric Bragg reflector
DCA	Dielectric continuum approximation
DCP	Dielectrophoretic cell patterning
D-CAP	Digitally-configurable analog processor
DEM	Dynamic element matching
DEP	Dielectrophoresis
DHI	Digital holographic imaging
DIBL	Drain-induced barrier lowering
DPD	Digital predistortion
DRIE	Deep reactive-ion etching

DSP	Digital signal processing
DUT	Devices-under-test
ECG	Electrocardiogram
EEG	Electroencephalogram
EEPROM	Electrically erasable programmable read only memory
EL	Electroluminescence
EM	Electromagnetic
ENOB	Effective number of bits
EPD	Endpoint detection
FACS	Flow-assisted Cell Sorting
FDTD	Finite difference time domain
FEOL	Front-end-of-line
FET	Field-effect transistor
FFT	Fast Fourier transform
FIR	Finite impulse response
FOM	Figure of merit
FOV	Field of view
FPGA	Field programmable gate array
GeOI	Germanium-on-insulator
GMR	Giant magnetoresistance
GOI	Germanium-on-insulator
GP	Geometric programming
HD	Harmonic distortion
HDQ	Harmonic Differential Quadrature
HEMT	High-electron mobility
HIC	High-index-contrast
HM	Herringbone mixer
HOI	Heterostructure on insulator
HSQ	Hydrogen silsesquioxane
ICEO	Induced charge electro-osmosis
IDE	Interdigitated electrodes
IMD	Inter-modulation distortion
INL	Integral nonlinearity
ISI	Inter symbol interference
ISM	Industrial, scientific, medical
ITO	Indium-tin-oxide
IV	Current voltage
KOH	Potassium hydroxide
LED	Light-emitting device
LINC	Laboratory instrument computer
LNA	Low noise amplifier
LPCVD	Low pressure chemical vapor deposition
LSB	Lower sideband
MAA	methacrylic acid
MDLL	Multiplying delay-locked loops
MEM	Micro-electro-mechanical
M-HEMT	Metamorphic high-electron-mobility transistor
MEMS	Micro-electro-mechanical systems
MGA	Micro gas analyzer
MMA	Methylmethacrylate
MMSE	Minimum mean square error
MMW	Millimeter-wave
MOCVD	Metallorganic chemical vapor deposition
MOR	Model-order-reduction
MOS	Metal-oxide-semiconductor
MOSFET	Metal-oxide-semiconductor field-effect transistor

MPIE	Mixed-potential-integral-equation	SMU	Sense-Measurement Unit
MRAM	Magnetic-random-access memory	SNR	Signal-to-noise ratio
NEM	Nano-electro-mechanical	SOA	Semiconductor optical amplifier
NIL	Nanoimprint lithography	SoC	System-on-chip
NMOS	Negative-channel metal-oxide semiconductor	SOG	Singlet oxygen generator
OEO	Optical-electronic-optical	SOI	Silicon on insulator
OFDM	Orthogonal frequency division multiplexing	SOLES	Silicon on lattice-engineered substrate
OFET	Organic field-effect transistor	SPLEBL	Spatial-phase-locked electron-beam lithography
OFF	Off	SPM	Scanning probe micrograph
OHC	Outer hair cells	SRAM	Static random access memory
OLED	Organic light-emitting diode	SSDSOI	Strained-silicon directly on insulator
OPL	Optical projection lithography	STI	Shallow trench isolation
PA	Power amplifier	TAT	Trap-assisted tunneling
PAE	Power-added efficiency	TDC	Time-to-digital
PCR	Polymerase chain reaction	TDD	Threading dislocation density
PDAC	poly diallyldimethylammonium chloride	TERS	Tip enhanced Raman spectroscopy
PDMS	Polydimethylsiloxane	TIPS	Thermal inkjet pico-fluidic drop dispensing system
PECVD	Plasma enhanced chemical vapor deposition	TPV	Thermophotovoltaic
PEM	Proton exchange membrane; polymer electrolyte membrane	TTTDD	Time-temperature threading dislocation density
PFM	Pulse frequency modulation	UHVCVD	Ultra high vacuum chemical vapor deposition
PHEMT	Pseudomorphic high-electron mobility transistor	ULSI	Ultra Large Scale Integration
PHY	Physical layer	UWB	Ultra-wideband
PIV	Particle image velocimetry	VCO	Voltage Controlled Oscillators
PL	Photoluminescence	VCSEL	Vertical-cavity Surface-emitting Laser
PLL	Phase-locked loops	VDG	Voltage from Drain to Gate
PMGI	Polymethylglutarimide	VLS	Vapor-liquid-solid
PMMA	Polymethylmethacrylate	VLSI	Very Large Scale Integration
PMOR	Parameterized model reduction	VPR	Versatile Place and Route
PMOS	Positive channel metal oxide semiconductor	VSCEL	Vertical cavity surface-emitting laser
PPM	Pulse-position modulated	WiGLAN	Wireless gigabit local area network
PRF	Pulse-repetition frequency	WLAN	Wireless local area network
PROM	Parameterized reduced-order models	WSP	Water soluble particles
PSV	Pseudo-spin-valve	YSZ	Yttria-stabilized zirconia oxide
PTM	Predictive technology models	ZPAL	Zone-plate-array lithography
QCL	Quantum-cascade laser		
QD	Quantum dot		
RC	Resonant cavity		
RFID	Radio frequency identification		
RIE	Reactive-ion etching		
ROI	Regions of interest		
RSM	Response surface model		
RTNIL	Room-temperature nanoimprint lithography		
RVHI	Rainbow volume holographic imaging		
SAR	Successive approximation register		
SAW	Surface acoustic wave		
SBR	Saturable Bragg reflector		
SCE	Short-channel Effects		
SEBL	Scanning-electron-beam lithography		
SEM	Scanning-electron microscope		
SFDR	Spur-free dynamic range		
SGM	slanted groove mixer		
SHM	Staggered herringbone mixer		
SIMS	Secondary ion-mass spectrometry		
SiNW	Silicon nano-wire		
SiNWT	Silicon nanowire transistors		
SMR	Suspended microchannel resonator		